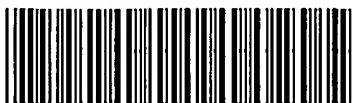


**Search Notes**

Application/Control No.

10/649,625

Examiner

Jim Vannucci

Applicant(s)/Patent under  
Reexamination

SEKI, YUICHI

Art Unit

2828

**SEARCHED**

Class	Subclass	Date	Examiner
372	32	6/21/2005	JV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
package, sensor, first laser, second laser	6/21/2005	JV